DOCUMENT CHANGE REQUEST

DCR number 1089
Changes required for: General
Originator: Samuel Savin
Date: 2024/02/29
Date sent: 2017/06/05
Organisation: STMicroelectronics
Status: IMPLEMENTED

Title:	Transistors, Power, MOSFET, N-Channel, RAD-HARD, based on Type STRH100N10FSY3		
Number:	5205/021	Issue:	10

Other documents affected:

5205/022-9, 5205/023-9, 5205/024-9, 5205/025-9, 5205/029-8

Page:

Paragraph:

APPENDIX ‘A’

Original wording:

The AC characteristics Ciss, Coss, Crss, Qg, Qgs, Qgd, td(on), tr, td(off), tf and trr may be considered guaranteed but not tested if successful pilot lot testing has been performed on the wafer lot in accordance with STMicroelectronics procedure 8212069, which includes AC (Ciss, Coss, Crss, Qg, Qgs, Qgd, td(on), tr, td(off), tf and trr) characteristic measurements per the Detail Specification.

Proposed wording:

The AC characteristics Ciss, Coss, Crss, Qg, Qgs, Qgd, td(on), tr, td(off), tf and trr may be considered guaranteed but not tested if successful pilot lot testing has been performed on the wafer lot in accordance with STMicroelectronics wafers acceptation internal procedure, which includes AC (Ciss, Coss, Crss, Qg, Qgs, Qgd, td(on), tr, td(off), tf and trr) characteristic measurements per the Detail Specification.

Justification:

Procedure 8212069 corresponded to the internal procedure for the Power Mosfet pilot lots. This procedure has been replaced by the generic procedure DMS 00111752 gathering all the hirel ST products with the French title Acceptation wafers pour utilisation haute fiabilité: Lots Pilotes .
STMicroelectronics would like to replace “STMicroelectronics procedure 8212069” by the “STMicroelectronics Wafers acceptation internal procedure“ for a long follow-up.

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Page:

Paragraph:

Appendix A

Original wording:

The AC characteristics Ciss, Coss, Crss, Qg, Qgs, Qgd, td(on), tr, td(off), tf and trr may be considered guaranteed but not tested if successful pilot lot testing has been performed on the wafer lot in accordance with STMicroelectronics procedure 8212069, which includes AC (Ciss, Coss, Crss, Qg, Qgs, Qgd, td(on), tr, td(off), tf and trr) characteristic measurements per the Detail Specification.

Proposed wording:

The AC characteristics Ciss, Coss, Crss, Qg, Qgs, Qgd, td(on), tr, td(off), tf and trr may be considered guaranteed but not tested if successful pilot lot testing has been performed on the wafer lot in accordance with STMicroelectronics "Wafers acceptation internal procedure", as specified in approved PID, which includes AC (Ciss, Coss, Crss, Qg, Qgs, Qgd, td(on), tr, td(off), tf and trr) characteristic measurements per
the Detail Specification.

Justification:

Just added a reference to the PID

Attachments:
N/A
Modifications:
Added: "as specified in approved PID"
Approval signature:
Date signed:
2024-02-29